

MITSUBISHI SEMICONDUCTOR <GaAs FET>  
**MGFC34S SERIES**

FOR MICROWAVE POWER AMPLIFIERS  
 INTERNALLY MATCHED

91D 10125 DT-39-07

**PRELIMINARY**

Notice This is not a final specification  
 Some parametric limits are subject to change

6249829 MITSUBISHI (DISCRETE SC)

**DESCRIPTION**

The MGFC34S series is an internally impedance matched GaAs power FET especially designed for use in C-band amplifiers. The hermetically sealed metal-ceramic package guarantees high reliability.

**FEATURES**

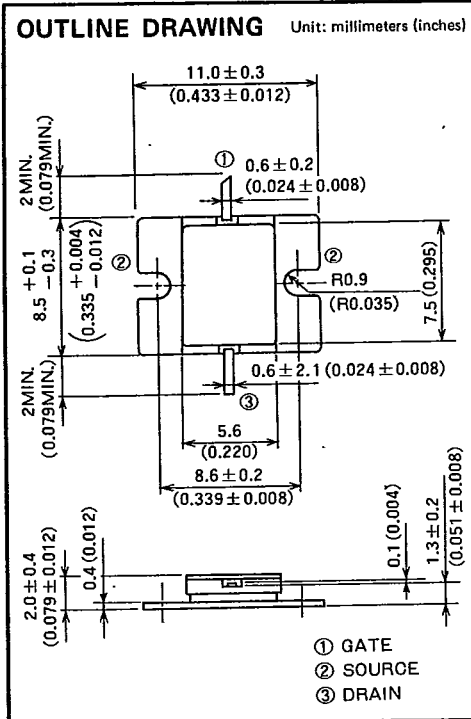
- Internally impedance matched
- Flip-chip mounted
- Small and light package
- High output power  
 $P_{1dB} = 2.5 \text{ W (TYP.) @ each frequency band}$
- High linear power gain  
 $G_{LP} = 10 \text{ dB (TYP.) @ each frequency band}$
- High power added efficiency  
 $\eta_{add} = 30\% \text{ (TYP.) @ each frequency band}$

**QUALITY GRADE**

- IG

**TYPE NUMBER**

Type Number	Frequency (GHz)
MGFC34S5258	5.2~5.8
MGFC34S5464	5.9~6.4
MGFC34S6471	6.4~7.1



**ABSOLUTE MAXIMUM RATINGS** ( $T_a = 25^\circ\text{C}$ )

Symbol	Parameter	Rating	Unit
$V_{GD0}$	Gate to drain voltage	-15	V
$V_{GS0}$	Gate to source voltage	-15	V
$I_D$	Drain current	2800	mA
$I_{GR}$	Reverse gate current	-9.0	mA
$I_{GF}$	Forward gate current	13.0	mA
$P_T$	Total power dissipation	18.75	W
$T_{oh}$	Channel temperature	175	$^\circ\text{C}$
$T_{stg}$	Storage temperature	-55 ~ +150	$^\circ\text{C}$
$R_{th(oh-o)}$	Thermal resistance	8	$^\circ\text{C/W}$

**ELECTRICAL CHARACTERISTICS** ( $T_a = 25^\circ\text{C}$ )

Symbol	Parameter	Conditions	Limits			Unit
			Min	Typ	Max	
$I_{DSS}$	Saturated drain current	$V_{DS} = 3V, V_{GS} = 0V$	1600	2200	2800	mA
$V_{GS(off)}$	Gate to source cut-off voltage	$V_{DS} = 3V, I_D = 10mA$	-2		-5	V
$g_m$	Transconductance	$V_{DS} = 3V, I_D = 1.1A$	600	1000		mS
$P_{1dB}$	Output power at 1 dB gain compression	$V_{DS} = 8V, I_D = 1.1A$ $f = 5.2 \sim 5.8GHz, 5.9 \sim 6.4GHz, 6.4 \sim 7.1GHz$	2	2.5		W
$G_{LP}$	Linear power gain		9	10		dB
$\eta_{add}$	Power added efficiency			35		%

**MGFC34S SERIES**

91D 10126 D

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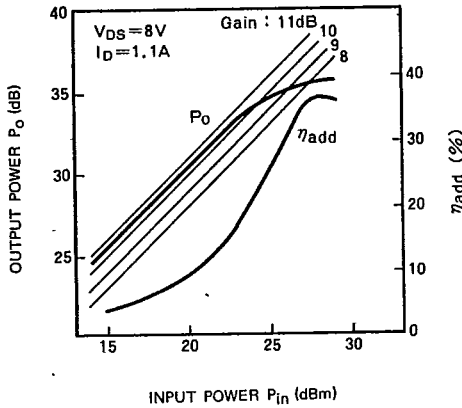
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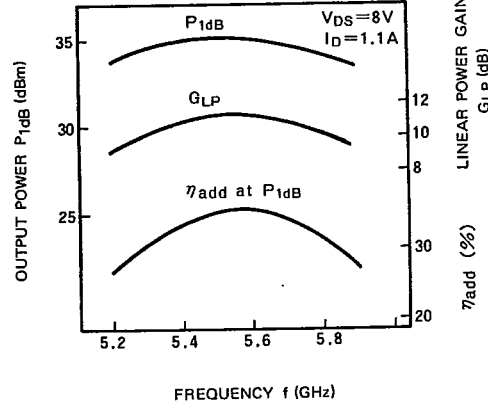
**TYPICAL CHARACTERISTICS (Ta=25°C)**

**MGFC34S5258**

**P<sub>o</sub>, η<sub>add</sub> vs. P<sub>in</sub>  
 (f = 6.5 GHz)**

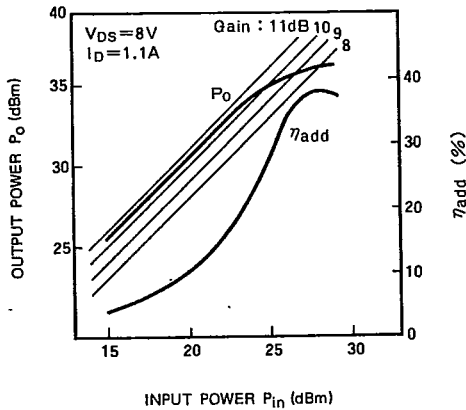


**P<sub>1dB</sub>, G<sub>LP</sub> & η<sub>add</sub> vs. f**

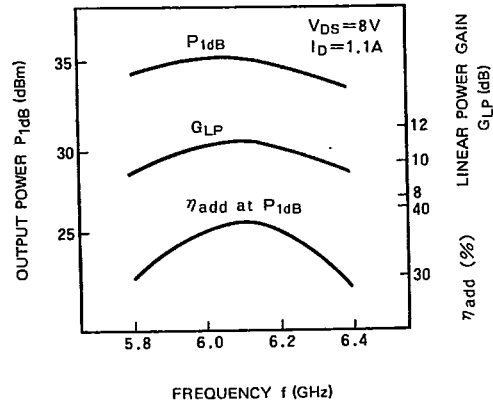


**MGFC34S5964**

**P<sub>o</sub>, η<sub>add</sub> vs. P<sub>in</sub>  
 (f = 6.15 GHz)**

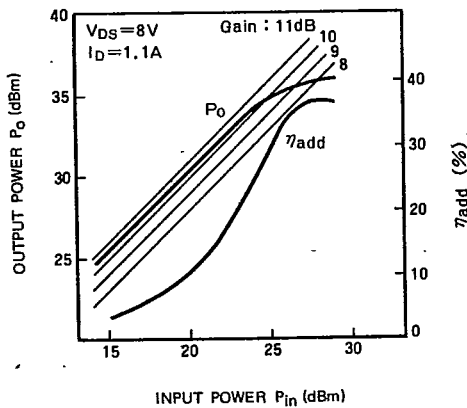


**P<sub>1dB</sub>, G<sub>LP</sub> & η<sub>add</sub> vs. f**

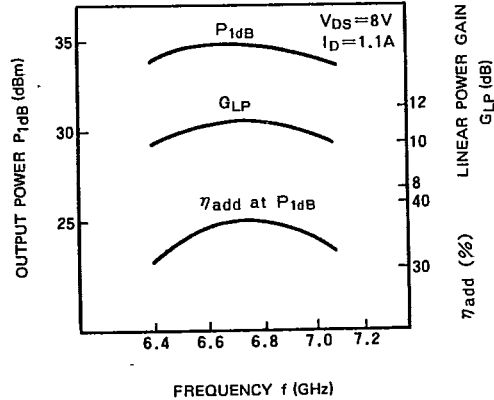


**MGFC34S6471**

**P<sub>o</sub>, η<sub>add</sub> vs. P<sub>in</sub>  
 (f = 6.75 GHz)**



**P<sub>1dB</sub>, G<sub>LP</sub> & η<sub>add</sub> vs. f**



**MGFC34S SERIES**

91D 10127 D

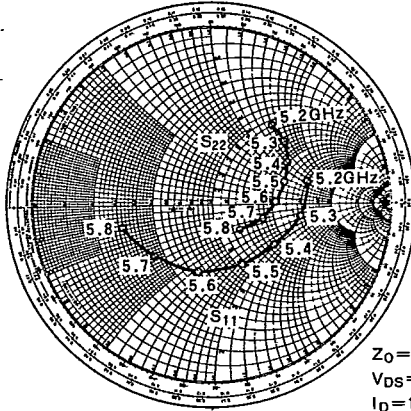
**FOR MICROWAVE POWER AMPLIFIERS  
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6249829 MITSUBISHI (DISCRETE SC)

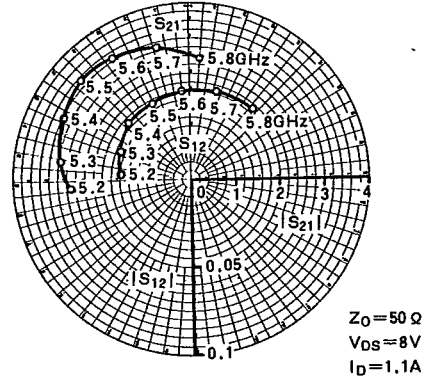
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MGFC34S5258

$S_{11}, S_{22}$  vs.  $f$

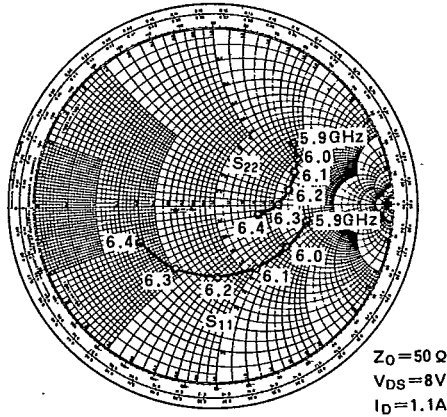


$S_{12}, S_{21}$  vs.  $f$

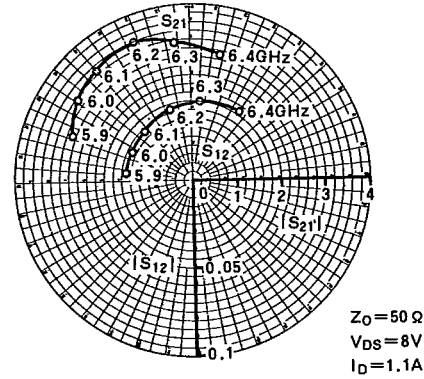


MGFC34S5964

$S_{11}, S_{22}$  vs.  $f$

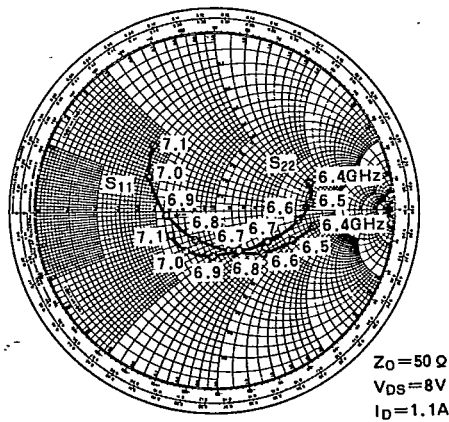


$S_{12}, S_{21}$  vs.  $f$

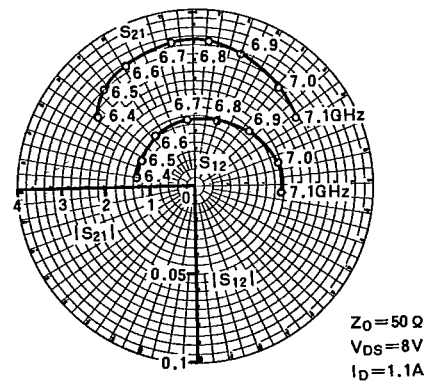


MGFC34S6471

$S_{11}, S_{22}$  vs.  $f$



$S_{12}, S_{21}$  vs.  $f$



**MGFC34S SERIES**

91D 10128 D

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**S PARAMETERS** ( $V_{DS}=8V, I_D=1.1A$ )

**MGFC34S5258**

f (GHz)	S Parameters (TYP.)							
	S <sub>11</sub>		S <sub>12</sub>		S <sub>21</sub>		S <sub>22</sub>	
	Magn.	Angle(deg.)	Magn.	Angle(deg.)	Magn.	Angle(deg.)	Magn.	Angle(deg.)
5.2	0.559	13	0.039	175	2.692	-176	0.566	52
5.3	0.502	-7	0.043	158	2.985	171	0.543	41
5.4	0.421	-34	0.047	133	3.199	153	0.481	29
5.5	0.375	-63	0.048	115	3.350	137	0.433	17
5.6	0.396	-102	0.051	94	3.236	121	0.361	1
5.7	0.437	-138	0.052	72	3.090	104	0.298	-16
5.8	0.526	-166	0.053	49	2.786	85	0.218	-39

**MGFC34S5964**

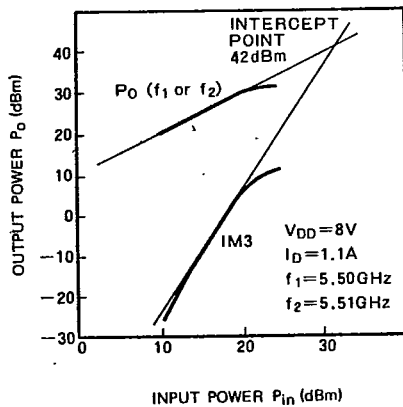
f (GHz)	S Parameters (TYP.)							
	S <sub>11</sub>		S <sub>12</sub>		S <sub>21</sub>		S <sub>22</sub>	
	Magn.	Angle(deg.)	Magn.	Angle(deg.)	Magn.	Angle(deg.)	Magn.	Angle(deg.)
5.9	0.531	-10	0.037	172	2.851	158	0.575	38
6.0	0.476	-30	0.037	152	3.199	144	0.546	30
6.1	0.437	-57	0.040	131	3.311	130	0.511	22
6.2	0.409	-87	0.041	107	3.350	112	0.448	11
6.3	0.425	-121	0.044	83	3.162	96	0.363	0
6.4	0.473	-153	0.047	56	2.884	77	0.266	-14

**MGFC34S6471**

f (GHz)	S Parameters (TYP.)							
	S <sub>11</sub>		S <sub>12</sub>		S <sub>21</sub>		S <sub>22</sub>	
	Magn.	Angle(deg.)	Magn.	Angle(deg.)	Magn.	Angle(deg.)	Magn.	Angle(deg.)
6.4	0.557	-10	0.033	170	2.692	144	0.566	16
6.5	0.464	-22	0.034	152	2.990	133	0.538	5
6.6	0.365	-42	0.036	128	3.199	119	0.471	-8
6.7	0.251	-74	0.038	96	3.311	99	0.349	-22
6.8	0.212	-125	0.039	70	3.273	84	0.268	-62
6.9	0.284	-173	0.044	45	3.162	70	0.277	-94
7.0	0.431	154	0.049	16	2.917	49	0.295	-125
7.1	0.516	133	0.049	-6	2.723	34	0.297	-153

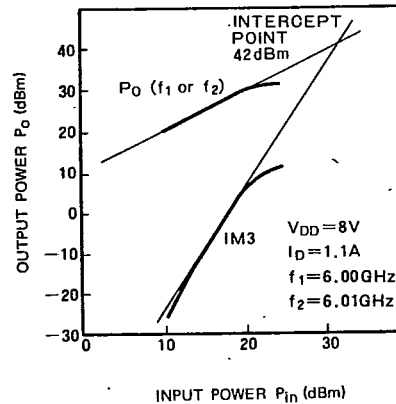
**MGFC34S5258**

**IM<sub>3</sub> vs. P<sub>in</sub>**



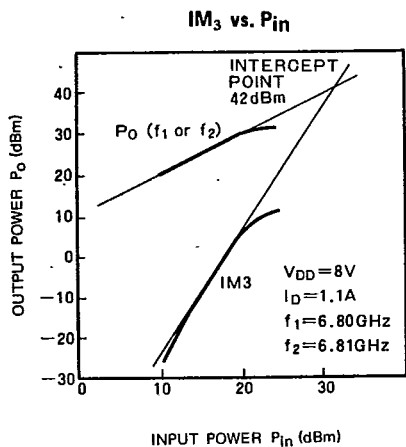
**MGFC34S5964**

**IM<sub>3</sub> vs. P<sub>in</sub>**



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MGFC34S6471



**HANDLING PRECAUTIONS**

**1. Check of Electrical Characteristics**

(1) Measurement of DC Characteristics by Curve Tracer  
 Many curve tracers, if not properly grounded, exhibit a high leakage current from the high-voltage transformer, which can be a prime cause of failure or degradation of the FET. Measurement of the DC characteristics using a curve tracer is therefore not recommended. However, when tests using a curve tracer are required, first of all, check that the curve tracer is grounded to earth.

(2) Measurement of RF Characteristics  
 Before measurement, check that the measuring instruments are grounded to earth. Many instruments to measure RF characteristics such as RF power meters, network analyzers and so on, if not properly grounded to earth, sometimes allow a high AC leakage of up to several tens volts, which can be a cause of failure or degradation of the FET.

**2. Installation of GaAs FET**

When GaAs FET is soldered on a microstrip circuit, the following should be attended to,

- (1) Properly ground the soldering iron to earth. Leakage current from the soldering iron could cause failure or degradation of the FET.
- (2) Solder the FET as promptly as possible at a low temperature. For a criterion, soldering in less than 8 seconds at a temperature of less than 250°C is recommended for each soldering process.

**3. Bias Procedure and Conditions**

When GaAs FET is biased, the following procedure is recommended.

- (1) Slowly adjust the gate to source voltage, V<sub>GS</sub>, to about -1V.
- (2) Gradually increase the drain to source voltage, V<sub>DS</sub>, from zero to a desired value.
- (3) Adjust the drain current, I<sub>D</sub>, to a desired value by controlling the gate to source voltage, V<sub>GS</sub>.

When bias is released, the reverse procedure is recommended.

Be careful that the FET is not operated under conditions exceeding absolute maximum ratings.

**4. Guaranteed Characteristics**

All the graphic characteristics illustrated in this catalog are typical examples. The characteristics of individual devices as specified in the tables of absolute maximum ratings and electrical characteristics are guaranteed under the specified conditions.